

Notice of References Cited	Application/Control No. 10/541,772		Applicant(s)/Patent Under Reexamination HATA ET AL.	
	Examiner ALI SOROUGH		Art Unit 1616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0163877	09-2003	Baker et al.	8/405
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-358124713-A	07-1983	Japan	Mizakumi et al.	A61K007/13
	O					
	P					
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	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	van Duffel et al., "Multilayered Clay Films: Atomic Force Microscopy Study and Modeling", 1999, Langmuir, Vol. 15 No. 22, pp. 7520-7529. (See IDS submission).
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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